

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/759,188	MITARASHI, MUTSUMI	
	Examiner	Art Unit	Page 1 of 1
	Angela M. Lie	2821	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,880,617	03-1999	Tanaka et al.	327/333
*	B	US-6,323,704	11-2001	Pelley et al.	327/112
*	C	US-6,353,333	03-2002	Curd et al.	326/81
*	D	US-6,366,141	04-2002	Chiba et al.	327/108
*	E	US-6,483,766	11-2002	Lee, Young-Dae	365/230.06
*	F	US-2002/0011883	01-2002	Yamazaki et al.	327/143
*	G	US-2002/0050849	05-2002	Hayashi et al.	327/333
*	H	US-2002/0118040	08-2002	Salminen, Vesa-Matti	326/81
*	I	US-2003/0001628	01-2003	Hsu et al.	327/103
*	J	US-6,496,044	12-2002	Nguyen et al.	327/108
*	K	US-6,392,439	05-2002	Tanaka et al.	326/68
*	L	US-6,504,400	01-2003	Tanaka et al.	326/68
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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